

WHAT IS CLAIMED IS:

1. A defect identifying apparatus, for inspecting and locating defects on an LCD substrate, said defect identifying apparatus comprising:
 - 5 a microscope, including at least one objective lens and a base;
 - a defect marker fixed to said base, wherein said defect marker locates a defect.
- 10 2. The defect identifying apparatus of claim 1, wherein said defect marker further includes a marking tip positioned between said objective lens and a focal plane of said objective lens.
- 15 3. The defect identifying apparatus of claim 1, wherein said defect marker further includes an ink jet.
4. A defect identifying apparatus, for inspecting and locating defects on an LCD substrate, said defect identifying apparatus comprising:
 - an inspection apparatus, including a base;
 - 20 a defect marker fixed to said base, said defect marker including an ink jet, wherein said ink jet marks a defect.
5. The defect identifying apparatus of claim 4, wherein said inspection apparatus is a microscope.

6. The defect identifying apparatus of claim 5, wherein said microscope further includes an objective lens.

7. The defect identifying apparatus of claim 6, wherein said ink jet is
5 positioned between said objective lens and a focal plane of said objective lens.